



SLOVENSKI STANDARD
SIST EN 169000:2004/A1:2004
01-januar-2004

Rodovna specifikacija: Kristalni oscilatorji - Dopolnilo A1

Generic Specification: Quartz crystal controlled oscillator

Fachgrundspezifikation: Quarzoszillatoren

Spécification générique: Oscillateurs pilotes par quartz

Ta slovenski standard je istoveten z: EN 169000:1992/A1:1998

[SIST EN 169000:2004/A1:2004](https://standards.iteh.ai/catalog/standards/sist/46b20562-a06b-4522-b89a-fd7be9f3e90b/sist-en-169000-2004-a1-2004)

<https://standards.iteh.ai/catalog/standards/sist/46b20562-a06b-4522-b89a-fd7be9f3e90b/sist-en-169000-2004-a1-2004>

ICS:

31.140	Piezelektrične in dielektrične naprave	Piezoelectric and dielectric devices
--------	--	--------------------------------------

SIST EN 169000:2004/A1:2004 **en**

iTeh STANDARD PREVIEW
(standards.iteh.ai)

[SIST EN 169000:2004/A1:2004](https://standards.iteh.ai/catalog/standards/sist/46b20562-a06b-4522-b89a-fd7be9f3e90b/sist-en-169000-2004-a1-2004)

<https://standards.iteh.ai/catalog/standards/sist/46b20562-a06b-4522-b89a-fd7be9f3e90b/sist-en-169000-2004-a1-2004>

Descriptors: Quality, electronic components, quartz crystal controlled oscillators

English version

**Generic Specification:
Quartz crystal controlled oscillators**

Spécification générale:
Oscillateurs pilotés par quartz

Fachgrundspezifikation:
Quarzoszillatoren

SIST EN 169000:2004/A1:2004

This amendment A1 modifies the European Standard EN 169000:1992; it was approved by CENELEC on 1993-10-15. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this amendment the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This amendment exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Czech Republic, Denmark, Finland, France, Germany, Greece, Iceland, Ireland, Italy, Luxembourg, Netherlands, Norway, Portugal, Spain, Sweden, Switzerland and United Kingdom.

CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

Central Secretariat: rue de Stassart 35, B - 1050 Brussels

© 1998 CENELEC - All rights of exploitation in any form and by any means reserved worldwide for CENELEC members.

ITEH STANDARD PREVIEW
(standards.iteh.ai)

Ref. No. EN 169000:1992/A1:1998 E

[SIST EN 169000:2004/A1:2004](https://standards.iteh.ai/catalog/standards/sist/46b20562-a06b-4522-b89a-fd17be9f3e90b/sist-en-169000-2004-a1-2004)

[https://standards.iteh.ai/catalog/standards/sist/46b20562-a06b-4522-b89a-](https://standards.iteh.ai/catalog/standards/sist/46b20562-a06b-4522-b89a-fd17be9f3e90b/sist-en-169000-2004-a1-2004)

[fd17be9f3e90b/sist-en-169000-2004-a1-2004](https://standards.iteh.ai/catalog/standards/sist/46b20562-a06b-4522-b89a-fd17be9f3e90b/sist-en-169000-2004-a1-2004)

Foreword

This amendment to the European Standard EN 169000:1992 was prepared by CLC/TC CECC/SC 49 (former WG 17).

The text of the draft based on document CECC(Secretariat)3336 was submitted to the formal vote; together with the voting report, circulated as document CECC(Secretariat)3454, it was approved as amendment A1 to EN 169000:1992 on 1993-11-02.

The following dates were fixed:

- latest date by which the amendment has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 1998-08-01
 - latest date by which the national standards conflicting with the amendment have to be withdrawn (dow) 1999-08-01
-

SIST EN 169000:2004/A1:2004

iTeh STANDARD PREVIEW
(standards.iteh.ai)

[SIST EN 169000:2004/A1:2004](https://standards.iteh.ai/catalog/standards/sist/46b20562-a06b-4522-b89a-fd17be9f3e90b/sist-en-169000-2004-a1-2004)

[https://standards.iteh.ai/catalog/standards/sist/46b20562-a06b-4522-b89a-](https://standards.iteh.ai/catalog/standards/sist/46b20562-a06b-4522-b89a-fd17be9f3e90b/sist-en-169000-2004-a1-2004)

[fd17be9f3e90b/sist-en-169000-2004-a1-2004](https://standards.iteh.ai/catalog/standards/sist/46b20562-a06b-4522-b89a-fd17be9f3e90b/sist-en-169000-2004-a1-2004)

2.2 Related documents^{*)}

	IEC 68-1	Replace by	(1981) (1988)	
	IEC 68-2-1	Replace by	(1974) (1983) (1976) (1990)	Amendment No.1 Supplement A
	IEC 68-2-17	Replace by	(1986) (1989)	Amendment No.1 Amendment No.3
	IEC 68-2-32	Replace by	(1982) (1990)	Amendment No.1 Amendment No.2
	IEC 68-2-58	Delete		
Add	IEC 695-2-2		(1980)	Fire hazard testing -- Part 2: Test methods Needle-flame test
	IEC 801-2	Delete		
Add	CECC 00 015/1		(1991)	Basic specification: Protection of electrostatic sensitive devices -- Part 1: General requirements
	CECC 00 111	Replace by	(1980) (1981) (1985) (1986) (1991)	Specifications Amendment No. 1 Amendment No. 2 Amendment No. 3 Specifications
Add	CECC 00 802		(1990)	CECC Standard method for specification of surface mounting components (SMDs) of assessed quality

*) References in this amendment do not necessarily refer to the latest issue of a published standard. The reader is therefore advised to consult the latest published version of the reference, so that the most up-to-date requirements/advice can be followed, when this is not in conflict with EN 169000 as amended.

2.3 Add the following definitions:

2.3.37 Storage temperature

The minimum and maximum temperature as measured on the enclosure at which the quartz crystal controlled oscillator may be stored without deterioration or damage to its performance.

2.3.38 Retrace characteristics

The ability of an oscillator to return to within specified limits of a previously stabilized frequency, following a storage period in the unenergized condition.

2.5.1 Amend the second line to read:

“.....(7) in the order below”

Add:

- (11) Surface mount device classification (if applicable)
(see 6.2 of CECC 00 802)

SIST EN 169000:2004/A1:2004

3.1 Replace “5.2.8 of CECC 00 111 Part I” by “2.2.6 of CECC 00 111 Part III”.

4.2.6 (2) Replace “(see IEC 801-2)” by “(see CECC 00 015/1)”.

4.6.2 (2) Fine leak test

Add at the end of the first paragraph:

Care should be taken to ensure that the pressure chosen does not cause mechanical damage to the device under test.

Replace the 2nd paragraph by:

For oscillators using unencapsulated crystal vibrators the maximum leak rate shall be 10^{-3} Pa cm³/s (10^{-8} mbar l/s).

For oscillators using sealed crystal units the leak rate shall be 10^{-1} Pa cm³/s (10^{-6} mbar l/s) unless otherwise stated in the detail specification.

4.6.3 (1) Solderability Test B

Replace “Test Td of IEC 68-2-58” by “7.2.1 of CECC 00 802”^{*)}.

4.6.3 (2) Resistance to soldering heat Test B

Replace ”Test Td of IEC 68-2-58”by “7.2.2 of CECC 00 802”^{*)}.

4.6.4 Amend title to read:

Rapid change of temperature, two-fluid-bath method

4.6.5 Amend title to read

Rapid change of temperature with prescribed time transition

Amend contents on page 2 to reflect the above changes of title.

Add: [SIST EN 169000:2004/A1:2004](#)

4.6.23 Flammability test (destructive)

(1) Self ignition

Due to the wide range of designs, materials, added components and operating conditions used, no specific test is called up. Customers and manufacturers are advised that their individual electrical and mechanical designs should minimize the risk of self ignition when operated or stored within the limits of their specifications. This particularly applies to oven controlled crystal oscillators.

(2) Induced ignition

This test shall be performed in accordance with IEC 695-2-2 Needle-flame test. The detail specification shall state the severity of the duration of application of the test flame selected from 5 s, 10 s, 20 s, 30 s, 60 s or 120 s as appropriate to the design and materials of the test specimen.

The duration and extent of burning shall be stated in the detail specification.

^{*)} NOTE: The technical requirements of these two tests have not been changed. They are however more fully explained with appropriate guidance in CECC 00 802 (1990) CECC Standard method for specification of surface mount components (SMDs) of assessed quality.